Characterization of Metal-Semiconductor Contacts using Circular **Transmission Line Measurement**

REU student: William Hale

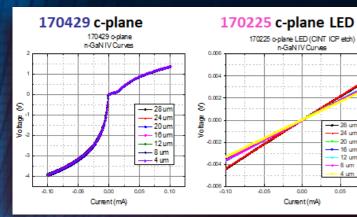
Mentors: Andrew Aragon, Kennneth DaVico, Ashwin Rishinaramangalam

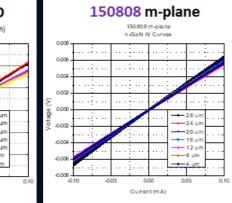
Background:

The current-voltage (IV) relationship of a LED's contacts effects the performance of the LED. Linear ohmic contacts are preferred over non-linear Schottky contacts, as ohmic contacts contribute to a lower series resistance. A lower series resistance equates to a smaller loss of power to thermal energy. Also, a lower series resistance contributes to a shorter RC time constant. A shorter RC time constant permits higher bandwidth modulation of LEDs.

In this chart we offer characterizations done on the IV relationships of various contacts fabricated on the c-plane and m-plane orientations of the GaN crystal lattice.

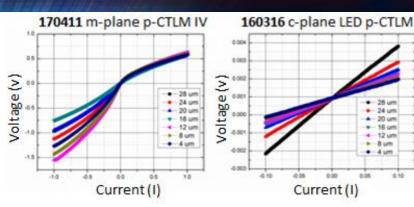
Results:



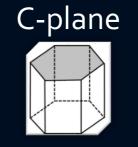




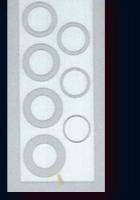


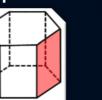


	N-CTLM Sample	Approximate Doping
	170429 c-plane n-GaN (not etched)	4 x 10 ¹⁶
	170225 c-plane LED (ICP etch @ CINT)	2 x 10 ¹⁸
	150808 m-plane n-GaN (Not etched)	2 x 10 ¹⁸
	160217 m-plane LED (ICP etch @ CINT)	2 x 10 ¹⁸



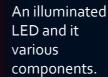
c-plane orientation of the GaN unit cell. M-plane





A Circular Transmission Line Measurement device

m-plane orientation of the GaN unit cell.



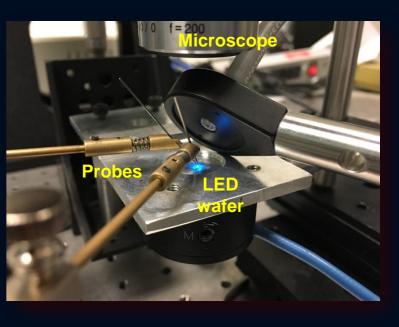
Conclusions:

Future Work:

Investigate how the contact geometry, in addition to the semiconductor doping, effects the IV characteristics and RC time constant of the device.



PI: Dr Daniel Feezell



Method:

Fabricated and tested CTLM devices on doped GaN and on fabricated LEDs. The CTLM device were fabricated on both n-GaN and P-GaN. For n-GaN various doping profiles were measured while on p-GaN the root mean square surface roughness was measured with an Atomic Force Microscope.

The doping profile is an important contributing factor to the current-voltage relationship of a device. By having proper doping profiles and having a smooth interfacial contact layer.